

Data fusion of photoluminescence (PL), SEM, and EDS mapping



- **Scanning Mini Pro PL microscope**

- 349 nm excitation kit
- Scanning and mapping
- β -Ga₂O₃ sample annealed in hydrogen
- Damage evident from annealing (SEM)
- Traces of Ga and Si in some damaged regions (EDS)
- Bright emitters from some damaged regions (PL)
- **Mini Pro cost ~20% of an SEM system**

